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Applicant	Alain BETHUNE et al.				
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U.S. PATENT DOCUMENTS						
Examiner Initial*	Document Number	Issue Date	Name	Class	Sub Class	Filing Date If Appropriate
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FOREIGN PATENT DOCUMENTS						
	Document Number	Publication Date	Country	Class	Sub Class	Translation Yes or No
STIK	JP 3-97009	10/1991	Japan			No
QU.	JP 5-294054	11/1993	Japan			English Abstract
SEK	JP 10-240131	9/1998	Japan			English Abstract
SEC	JP 6-60866	8/1994	Japan			No

	OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)
Stex	English Language Abstract of JP 5-294054
SRK	English Language Abstract of JP 10-240131
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